						· ····
FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) February 2, 2005			ATTY DOCKET NO. 03500.017420	APPLICAT	PLICATION NO. 1621,347	
			APPLICANT SHUICHI MURAKAMI ET AL.			
			FILING DATE July 18, 2003		GROUP 2861	
	February 2, 2003		U.S. PATENT DOCUMENTS	· <u>-</u>		
•EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
m m	6,676,241	01/2004	Yabe			02/2002
					·	
			·			
······································		F	DREIGN PATENT DOCUMENTS			
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATIO YES/NO/ OR ABSTRAG
₩	JP 6-312506	08/1994	Japan			Abstrac
	·					
			,			
		J				
	ОТ	HER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		
EXAMINER	Sampy	<u> </u>	DATE CONSIDERED 2/19			
AMINER: Initial if references	ence considered, whether orthot citation is	in conformance with MPEP	609; Draw line through citation if not in conformance and not conside	red. Include copy o	f this form with nex Sl	n communication to heet 1 of

DC_MAIN 191502v1

applicants. DWP/tmc

OT 2 0 2003 4

ATTY DOCKET NO. APPLICATION NO. FORM PTO 1449 (modified) 03500.017420 10/621,347 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE APPLICANT SHUICHI MURAKAMI ET AL. LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) GROUP FILING DATE July 18, 2003 Unassigned October 20, 2003 U.S. PATENT DOCUMENTS *EXAMINER DOCUMENT FILING DATE NUMBER DATE SUBCLASS INITIAL NAME CLASS 04/1987 4,657,631 Noguchi 06/1993 5,218,376 Asai 12/2000 6,155,673 Nakajima et al. 6,350,016 B1 02/2002 Tachihara et al. 09/2002 6,443,561 B1 Murakami 02/2003 6,520,626 B1 Murakami 6,540,335 B2 04/2003 Touge et al. FOREIGN PATENT DOCUMENTS TRANSLATION YES/NO/ OR ABSTRACT DOCUMENT DATE COUNTRY CLASS SUBCLASS NUMBER JP 4-10940 A 01/1992 Japan Abstract* JP 4-10941 A 01/1992 Japan Abstract* U.S. JP 6-45242 B2 06/1994 Japan Counterpart OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.) *Note: U.S. counterpart patents also submitted (see text of IDS). **EXAMINER** 5 ه DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or rigid citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to

Sheet 1 of 1

DC_MAIN 147459v1

applicants.

DWP/tmc